Surface imaging is only one part of the SIMSLAB picture.

The VG SIMSLAB has a unique microfocused liquid metal ion beam that offers the surface scientist one of the most exciting new tools for elemental mapping — high resolution imaging — allowing the user to view rapidly the secondary electron images and ion maps over a wide range of materials.

In addition, the depth profiling capability of the SIMSLAB is enhanced by the ultra high vacuum system and the high performance mass analyzer. The Duoplasmatron ion source allows the measurement of trace elements over a wide dynamic range of concentrations vs. depth, permitting the user to plot the concentration profiles accurately.

SIMSLAB is the ideal tool for surface and in-depth analysis. It is designed to operate as a completely integrated SIMS system. SIMSLAB also incorporates the VG concept of modularity, which permits the addition of various sample supports tailored for your specific applications or other surface analysis techniques such as ESCA, Auger, ISS and AES.

Let VG put you in the picture with SIMSLAB.



VG INSTRUMENTS

VG Instruments, Inc. 300 Broad Street Stamford, CT 06901 (203) 322-4546 MBE LC-MS ICP-MS Surface Analysis Gas Analysis MS Mass Spectrometers



9800 McKnight Road, Suite 327 Pittsburgh, Pennsylvania 15237 U.S.A. NON-PROFIT ORG.
U.S. Postage
PAID
Pittsburgh, PA
Permit No. 1807

COMING IN THE NEXT ISSUE

- Preview of 1986 MRS Fall Meeting and Exhibit
- High-Gain Capsules for Inertial Fusion
- Development of Modeling of the Solidification Process
- Mechanical Properties Microprobe

Publications from

1986 MRS FALL MEETING

The following prices are effective until March 30, 1987. Prices after this date will be higher. Order your copies today to receive priority shipment.

Volume 74

Symposium A

Beam-Solid Interactions and Transient Processes

Editors: S.T. Picraux, M.O. Thompson, J.S. Williams

MRS Members \$34.00

U.S. Nonmembers \$39.00 Foreign Nonmembers \$44.00

Volume 75

Symposium B

Photon, Beam and Plasma Stimulated Chemical Processes

at Surfaces

Editors: V.M. Donnelly, I.P. Herman, M. Hirose

MRS Members \$34.00

U.S. Nonmembers \$39.00

Foreign Nonmembers \$44.00

Volume 76

Symposium C

Science and Technology of Microfabrication

Editors: R.E. Howard, E.L. Hu, S. Pang, S. Namba

MRS Members \$32.00

U.S. Nonmembers \$38.00

Foreign Nonmembers \$43.00

Volume 77

Symposium D

Interfaces, Superlattices, and Thin Flims

Editors: J.D. Dow, I.K. Schuller, J. Hilliard

MRS Members \$42.00

U.S. Nonmembers \$48.00

Foreign Nonmembers \$52.00

Volume 78

Symposium E

Advances in Structural Ceramics

Editors: P.F. Becher, M.V. Swain, S. Somiya

MRS Members \$26.00

Foreign Nonmembers \$37.00 U.S. Nonmembers \$32.00

Volume 79

Symposium F

Scattering, Deformation and Fracture in Polymers

Editors: B. Crist, T.P. Russell, E.L. Thomas, G.D. Wignall

MRS Members \$26.00

U.S. Nonmembers \$32.00 Foreign Nonmembers \$37.00

Volume 80

Symposium G

Science and Technology of Rapidly Quenched Alloys

Editors: M. Tenhover, L.E. Tanner, W.L. Johnson

MRS Members \$34.00

U.S. Nonmembers \$39.00 Foreign Nonmembers \$44.00

Volume 81

Symposium H

High-Temperature Ordered Intermetallic Alloys

Editors: C.C. Koch, C.T. Liu, N.S. Stoloff, O. Izumi

MRS Members \$30.00

U.S. Nonmembers \$38,00 Foreign Nonmembers \$48.00

Volume 82

Symposium I

Characterization of Defects in Materials

Editors: R.W. Siegel, R. Sinclair, J.R. Weertman

MRS Members \$32.00

U.S. Nonmembers \$37.00 Foreign Nonmembers \$42.00

Volume 83

Symposium J

Physical and Chemical Properties of Thin Metal Overlayers

and Alloy Surfaces

Editors: D.M. Zehner, D.W. Goodman

MRS Members \$26.00

U.S. Nonmembers \$31.00

Foreign Nonmembers \$36.00

Volume 84

Symposium L

Scientific Basis for Nuclear Waste Management

Editors: J.K. Bates, W.B. Seefeldt

MRS Members \$45.00

U.S. Nonmembers \$50.00

Foreign Nonmembers \$55.00

Volume 85

Symposium M

Microstructural Development During the Hydration of Cement

Editors: L. Struble, P. Brown

MRS Members \$29.00

U.S. Nonmembers \$34.00

Foreign Nonmembers \$39.00

Volume 86

Symposium N

Fly Ash and Coal Conversion By-Products Characterization,

Utilization and Disposal III

Editor: G.J. McCarthy MRS Members \$32.00

U.S. Nonmembers \$37.00

Foreign Nonmembers \$42.00

Volume 87

Symposium O

Materials Processing in the Reduced Gravity Environment of Space

Editors: R.H. Doremus, P.C. Nordine

MRS Members \$26.00

U.S. Nonmembers \$29.00 Foreign Nonmembers \$33.00

Volume 88

Symposium P

Optical Fiber Materials and Properties

Editors: S.R. Nagel, G. Sigel, J.W. Fleming, D.A. Thompson

MRS Members \$28.00

U.S. Nonmembers \$34.00 Foreign Nonmembers \$39.00

Volume 89

Symposium Q

Diluted Magnetic (Semimagnetic) Semiconductors

Editors: J.K. Furdyna, R.L. Aggarwal, S. von Molnar

MRS Members \$27.00

U.S. Nonmembers \$32.00

Foreign Nonmembers \$38.00

Volume 90

Symposium R

Materials for Infrared Detectors and Sources

Editors: J.F. Schetzina, J.T. Cheung, R.F.C. Farrow

MRS Members \$27.00

U.S. Nonmembers \$32.00

Foreign Nonmembers \$38.00

EXTENDED ABSTRACTS FROM THE 1986 FALL MEETING

EA-8 Symposium K

Graphite Intercalation Compounds

Editors: M.S. Dresselhaus, G. Dresselhaus, S.A. Solin MRS Members \$8.00 U.S. Nonmembers \$10.00

Foreign Nonmembers \$10.00

EA-9 Symposium S

Superconducting Materials Editors: J. Bevk, A.I. Braginski

MRS Members \$8.00 U.S. Nonmembers \$10.00

Foreign Nonmembers \$10.00

EA-10 Symposium U

Fractal Aspects of Materials

Editors: D.W. Schaefer, S.H. Liu, R.B. Laibowitz, B.B.

Mandelbrot

MRS Members \$8.00 U.S. Nonmembers \$10 00

Foreign Nonmembers \$10.00

Materials Research Society 1986 Fall Meeting

December 1-6

Boston Marriott Hotel
The Westin Hotel
Copley Place
Boston, Massachusetts

Details in this issue . .

- Technical Symposia
- Forum on the MSE Study
- Short Courses
- Job Placement Center
- Equipment Exhibit
- Registration Forms